AGD-317R

Rev.A1.0

Environment Test Report

Report NO: 11P020030

Summary	☑ **Pass** ☐ **Fail** Note : There is/are ___ defect(s) not list in the report, please check it in the DTS Website. ☐ **Pass with Deviation** **Comment:** ______________________________

Issue date	Approval	Test Engineer
2011-10-27	**Jansin Lee**	**Clement Chien**

Test item list

Testing Result

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

Configuration of EUT

Host :

Item	Device Information		
SYSTEM PC Model / Ver.	GES-5500F A1.0		
CPU Board	IMBI-QM57 A1.0		
BIOS / Version	GES-5500F Rev0.4(11/23/2010)		
CPU Type	Intel Core CPU i5-520M 2.40GHz		
Memory Type	DSL DDR3-1066 2GB(ELPIDA J1108BDSE-DJ-F)		
SATA HDD	Fujitsu MH72080BH G2 80GB		
USB DVD-ROM	MSI UO881-P		
LCD Monitor	AGD-317R-HTT-A2		
Operating System	☒	Windows 7 Professional English 32 Bit	
DC Adapter	FSP084-DMAA1 100-240V		

Num	Item	Spec
1.	**System**:	AGD-317R
	1.ExtendClient/Rx Board	PER-T212.Rev.A0.3_0_0
	2.Extend Host/Tx Board	PER-T210.Rev.A0.3_0_0
	2. Panel	AUO 17” SXGA(1280*1024) TFT LCD Display
	3. Touch Board	EETI S5000CEGG Rev : V1.08D1
	4. Inverter Board	QF132V1 NO : 171823
	5. Test Software	Windows 7 / Run one Microsoft media play simultaneously
2.	Adapter :	FSP060-DBAB1 AC-DC 12V / 5A

Temperature rise test

Test Date: 10-27-2011

Test Product: AGD-317R

Test Site: AAEON QE Internal Lab.

Test Standard: Reference EN 61131-2(94), UL508 (94)

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: AGD-317R
Date of Calibration: 10/12/2011
Serial Number: 12A323190

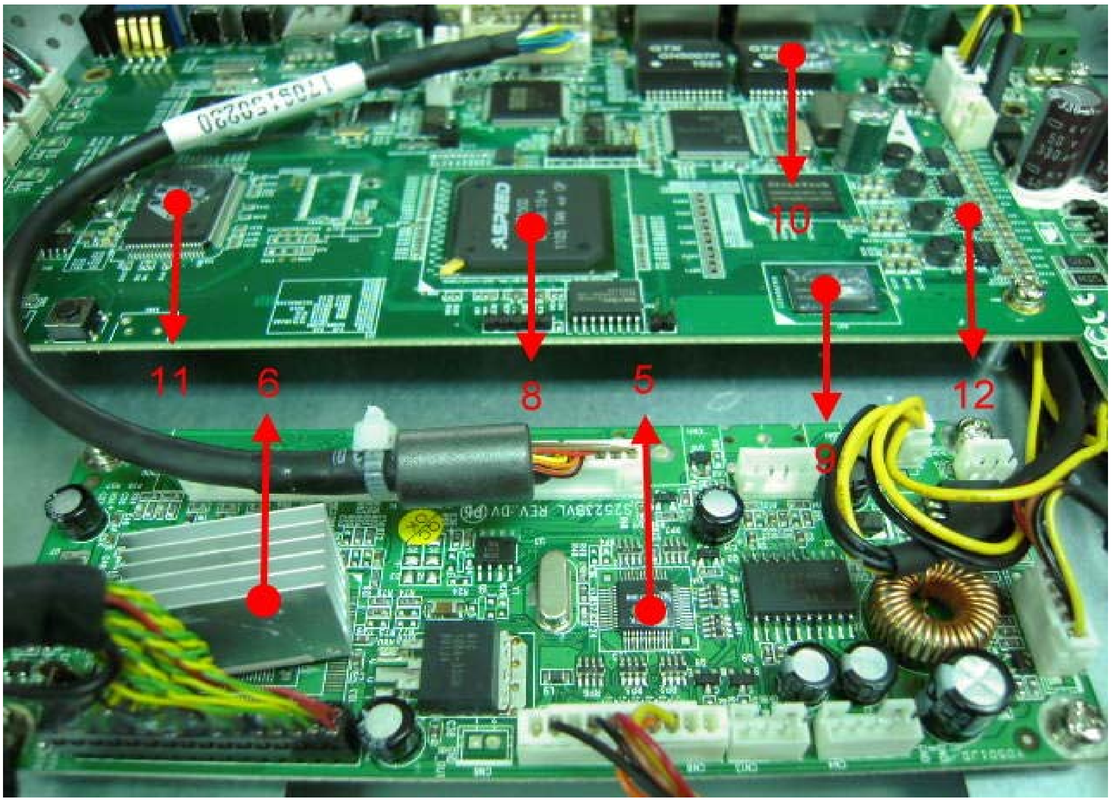
Test Condition:

Ambient temperature: 50℃
Continuous running till thermal stability (within less than 1℃)

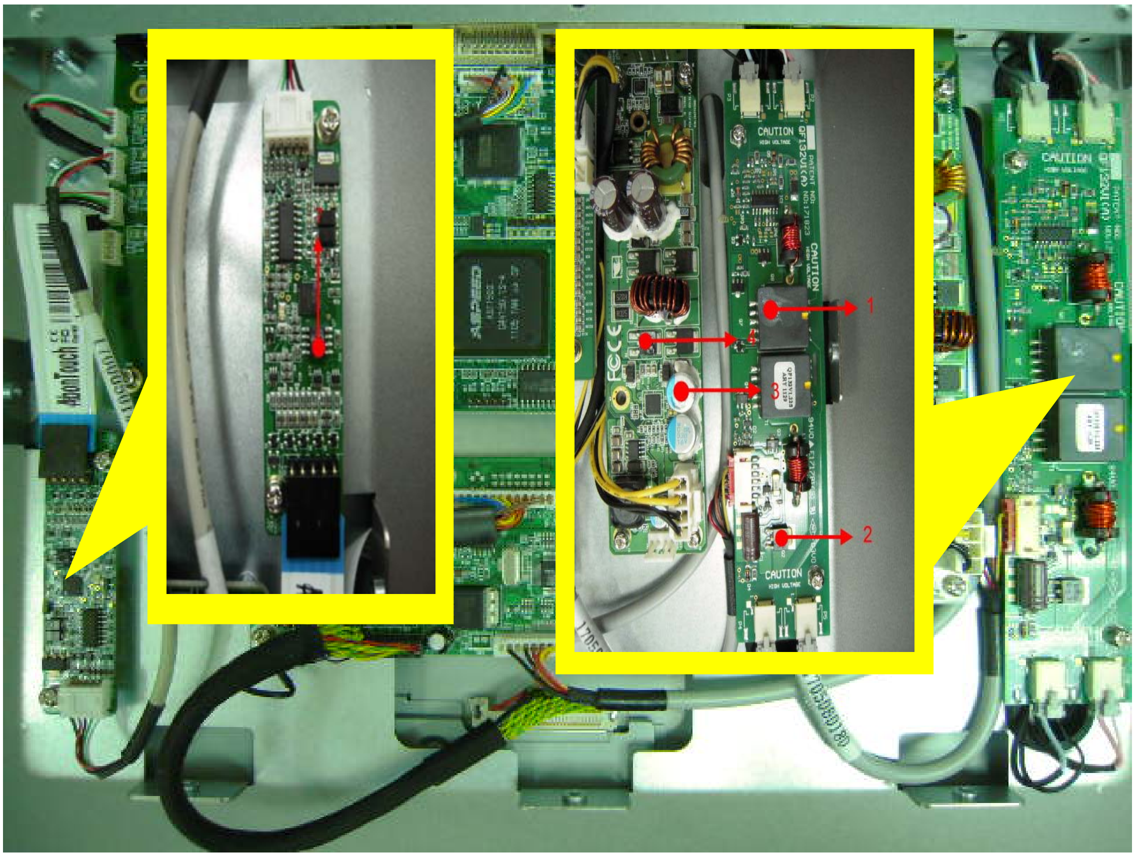
Test Software:

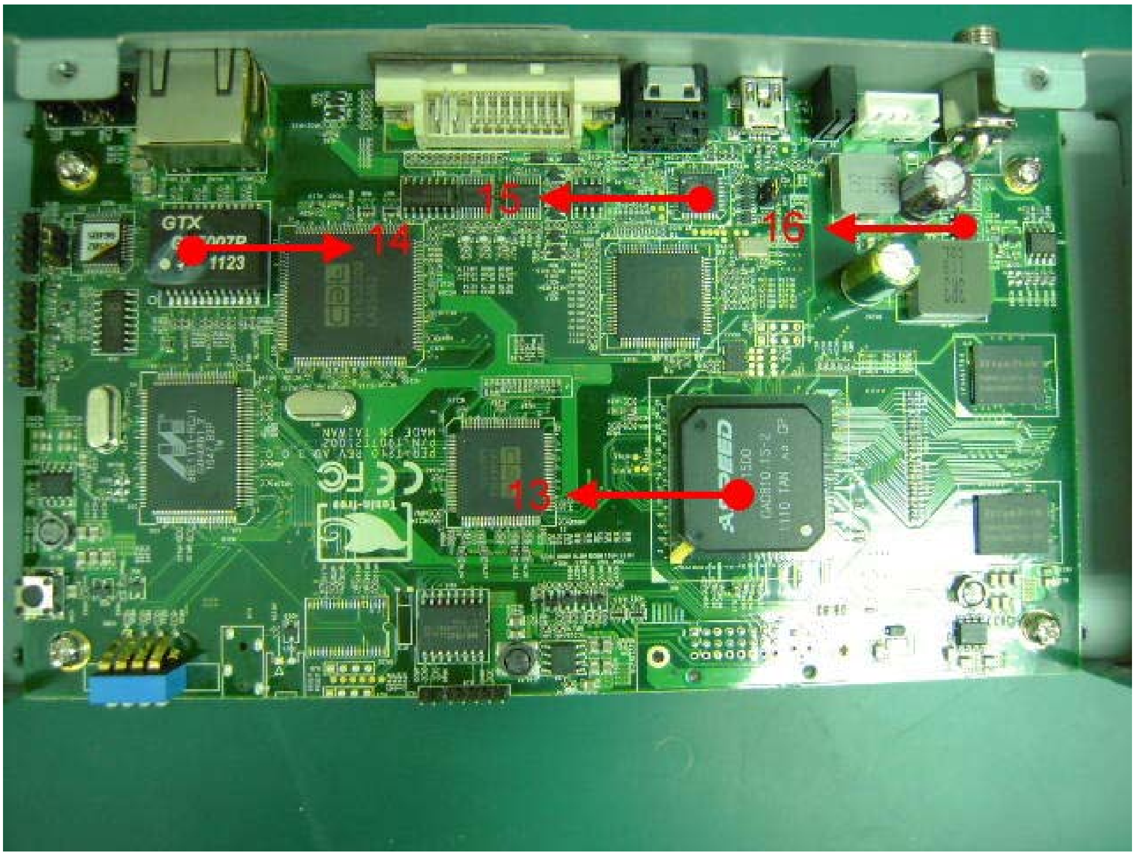
Windows 7 / Run one Microsoft media play simultaneously

Terminal Recorder:

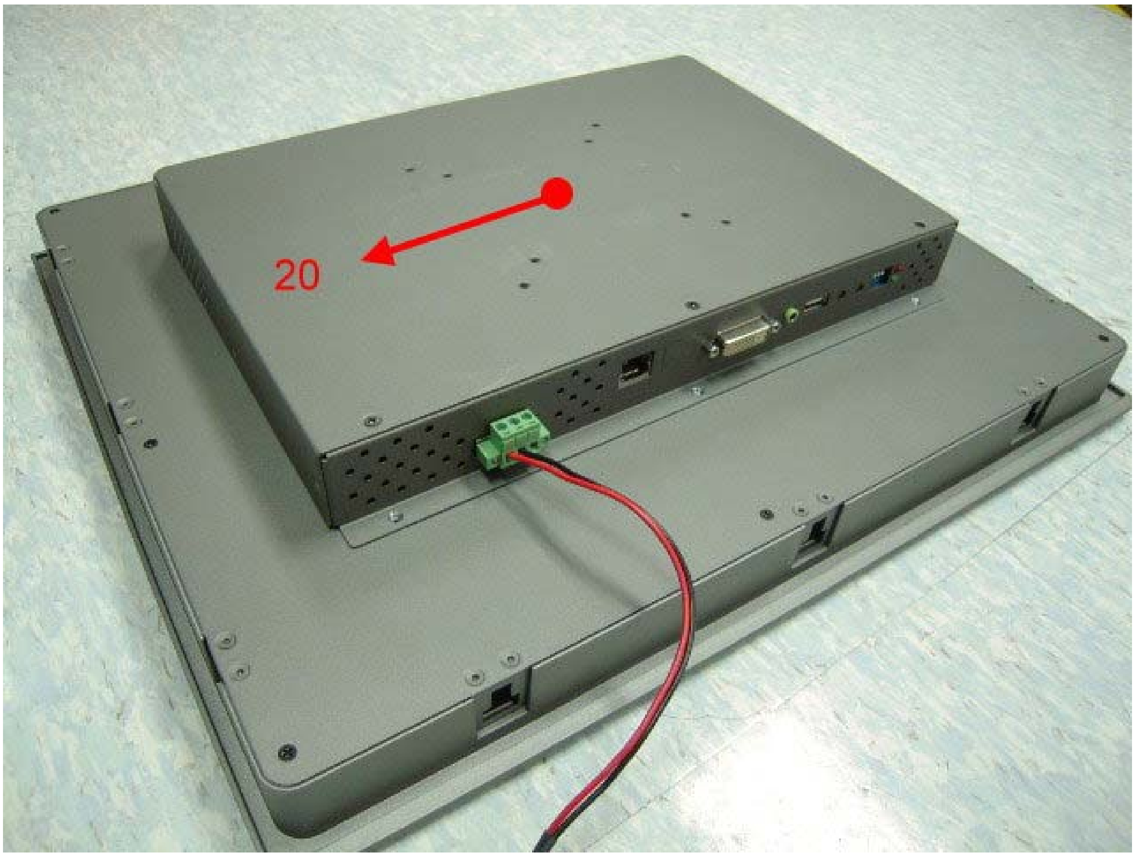


Temperature rise test





Temperature rise test



Temperature rise test

Thermal profile data:

Point / Temp. Stage(℃)	Spec	50	25
QF132V1 NO : 171823			
01. T2 – QF132V 1.16S ABG0706	135	91.3	66.3
02. Q5 – 1A41AP FDD8896	130	112.9	87.9
PER-P17D			
03. C32 – 330u.16v	125	75.6	50.6
04. Q5 – 1A41AP FDD8896	130	77.0	52.0
S2523BVL			
05. U4 - REALTEK RTD2120L A6M2002	85	83.9	58.9
06. U8 - REALTEK RTD2555 LH	85	78.7	53.7
EETI S5000CEGG Rev : V1.08D1			
07. U4 – EETI S458XRUP	85	67.3	42.3
Extender HDMI Client/Rx Board.PER-T212			
08.SU8 - (TF)PBGA487.W/O ASPEED LOGO.ASPEED.AST1500A3-GP	95	83.7	58.7
09.SU7 - (TF)DDRII-SDRAM 400MHz.512Mbits(32M*16bit).Etron.EM68B16CWPA-25H	100	85.2	60.2
10.SU26 - (TF)100/1000 Base Transformers.GOTREND.GTX-GH5007P	85	72.8	47.8
11.SU6 – (TF)Gigabit Ethernet Transceiver.MARVELL.88E1111B2-RCJ1C000	100	89.9	64.9
12.SU2 - (TF)2A Synchronous.Step down Converter.ITE.CAT7810CA	100	88.9	63.9
Extender Host/Tx Board.PER-T210			
13. HU1 - (TF)IC.SMD.PBGA487.W/O ASPEED LOGO.ASPEED.AST1500A3-GP	95	77.4	52.4
14. HU19 - (TF)100/1000 Base Transformers.GOTREND.GTX-GH5007P	85	68.6	43.6
15. HU59 - (TF)AUDIO CODEC.REALTEK.ALC5624-GR	100	72.3	47.3
16. HU60 - (TF)PWR.N-Channel.30V.16A.FAIRCHILD.FDS6688S	100	98.2	73.2
17. Control Box Inside Air Temperature (Panel)	N/A	68.9	43.9
18. Control Box Inside Air Temperature	N/A	70.4	45.4
19. Control Box Surface Temperature	N/A	57.8	32.8
20. Control Box Surface Temperature (Panel)	N/A	60.0	35.0
14. Chamber Air Temperature	N/A	50.1	25.1
Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.			

Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-317R)

Test Result:

No problem was found during the temperature rise operation test.

Temperature cycle test

Test Date: 10-24 ~ 26-2011

Test Product: AGD-317R

Test Site: AAEON QE Internal Lab.

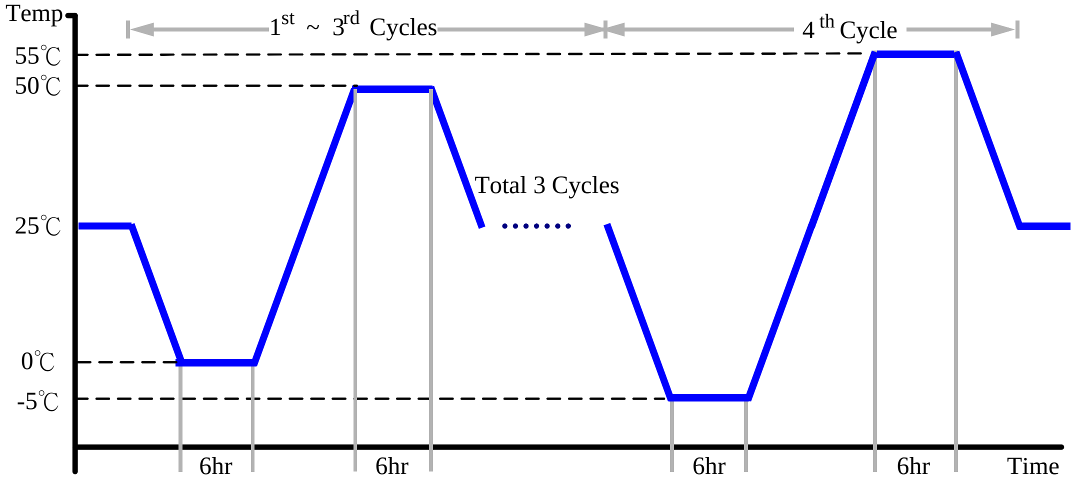
Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Test Condition:

1. Test Low Temperature: 0℃ (1~3 cycles)
   -5℃ (4th cycle)
2. Test High Temperature: 50℃ (1~3 cycles)
   55℃ (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2℃/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-317R)

Test Result:

No problem was found during the temperature operation cycle test.

High temperature storage test

Test Date: 10-14 ~ 16-2011

Test Product: AGD-317R

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

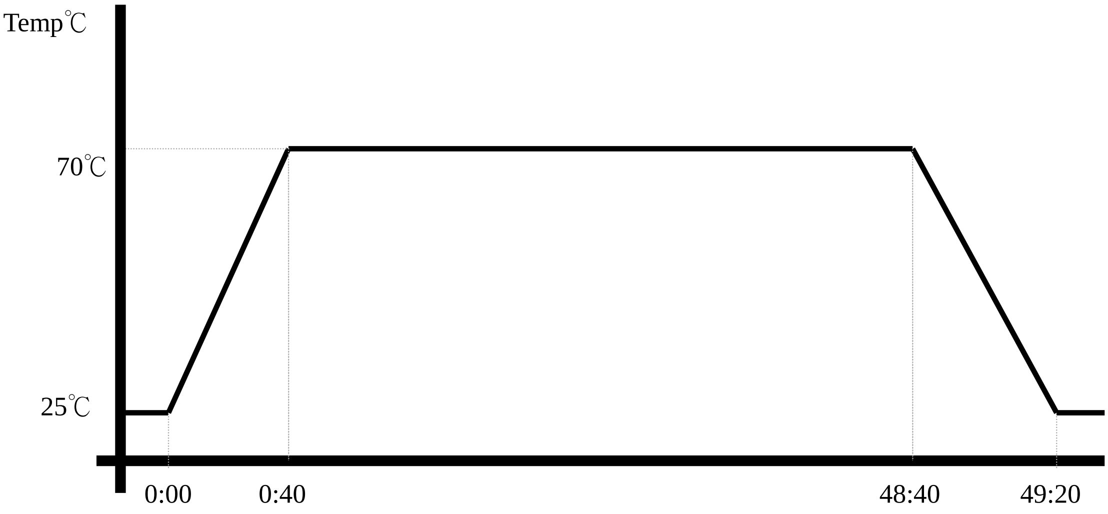
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

Date of Calibration: 12/02/10
Serial Number: 6487KT

Testing Item:

1. Test Temperature: 70℃
2. Test Times: 48Hrs
3. Test Software: Windows 7 / Run one Microsoft media play simultaneously
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AGD-317R)

Test Result:

No problem was found after the high temperature storage test.

Low temperature storage test

Test Date: 10-17 ~ 19-2011

Test Product: AGD-317R

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Testing Item:

1. Test Temperature: -20℃
2. Test Times: 48Hrs
3. Test Software: Windows 7 / Run one Microsoft media play simultaneously
4. Test Environment Curve:

Sample Configuration & Quantity Under Test:
Quantity: 1 (AGD-317R)

Test Result:
No problem was found after the low temperature storage test.

Humidity test

Test Date: 10-20 ~ 22-2011

Test Product: AGD-317R

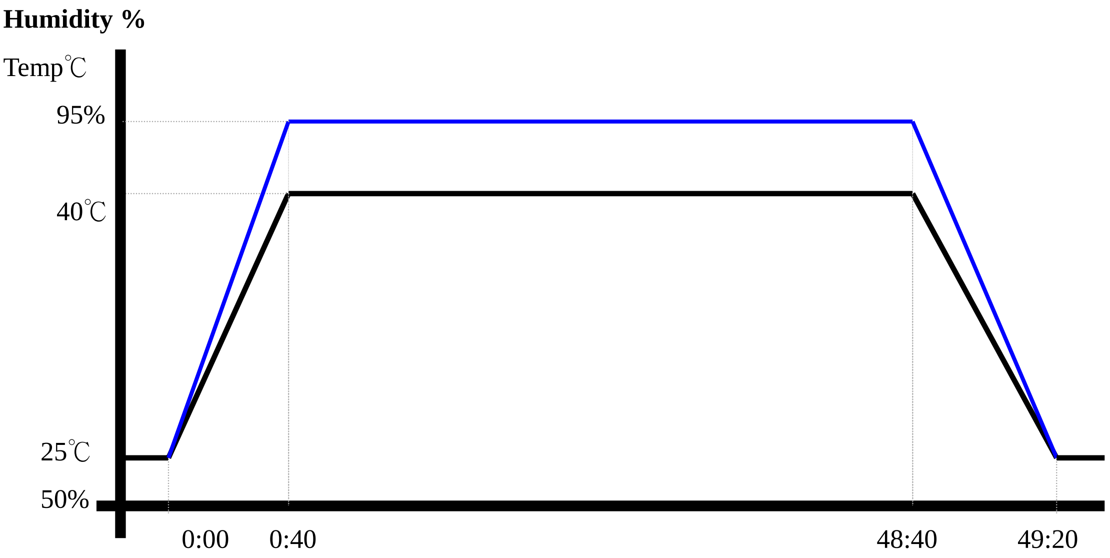
Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Testing Item:

1. Test Temperature: 40℃
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows 7 / Run one Microsoft media play simultaneously
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AGD-317R)

Test Result:
No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 10-22 ~ 23-2011

Test Product: AGD-317R

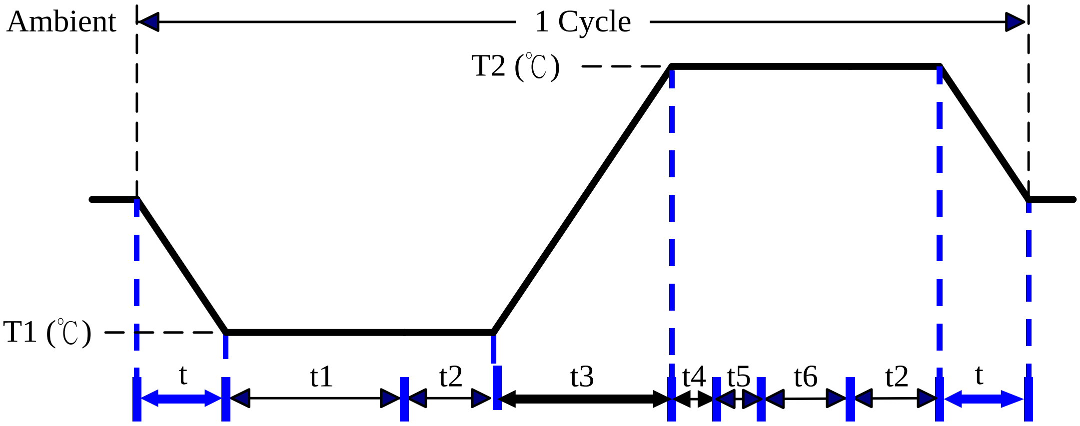
Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Test Condition:



Parameters	Description
T1	-5℃
T2	55℃
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2℃/min
n (Cycle)	1

t = temprature slope
t , t1, t6: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3, t4: Run media player
t5: Win 7 Software restart test 3 times
Test Software: Windows 7

Test Result:

a. No problem was found during the cold start test.
b. No problem was found during the hot start test.